

General Description

The WSD30N10DN56T is the highest performance SGT Dual N-Ch MOSFET with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The WSD46N10DN56 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

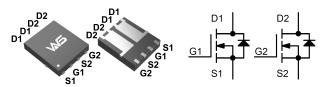
Product Summery

BVDSS	RDSON	ID
100V	70mΩ	12A

Applications

- DC-DC Converter.
- Motor Control.

DFN5X6C-8-EP2 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	±20	V
I _D @T _c =25℃	Continuous Drain Current, V _{GS} @ 10V	12	Α
I _D @T _c =100℃	Continuous Drain Current, V _{GS} @ 10V	7	А
I _{DM} a	Pulsed Drain Current	48	Α
E _{AS} ^b	Single Pulse Avalanche Energy	12	mJ
l _{AS} b	Avalanche Current 7		Α
P _D @T _c =25℃	Total Power Dissipation	31	W
T _{STG}	Storage Temperature Range -55 to 150		$^{\circ}$
T_J	Operating Junction Temperature Range -55 to 150		$^{\circ}$

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit	
R _{θJA} ^c	Thermal Resistance Junction-ambient		60	°C/W	
R _{θJC} ^c	Thermal Resistance-Junction to Case		4.0	°C/W	

Note a: Pulse width limited by max. junction temperature.

Note b: UIS tested and pulse width limited by maximum junction temperature 150°C (initial temperature T_i=25°C).

Note c: Surface Mounted on 1in² pad area.

Dual N-Ch MOSFET

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	100			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25 $^{\circ}{\mathbb{C}}$, I _D =1mA		0.098		V/°C
R _{DS(ON)} d	Static Drain-Source On-Resistance ²	V_{GS} =10V , I_D =6A		70	95	mΩ
R _{DS(ON)} d	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =4A		85	100	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.2	1.5	2.5	٧
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	VGS-VDS , ID -250UA		-5.52		mV/℃
	Drain Source Leakage Current	V _{DS} =80V , V _{GS} =0V , T _J =25℃			1	uA
I _{DSS}	Drain-Source Leakage Current	V_{DS} =80V , V_{GS} =0V , T_J =55 $^{\circ}\mathrm{C}$			30	
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, V_{DS} =0V			±100	nA
Rg ^e	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2.5		Ω
Qg ^e	Total Gate Charge (10V)	V _{DS} =30V , V _{GS} =10V , I _D =5A		16		
Q_gs^e	Gate-Source Charge			2.8		nC
Q_{gd}^e	Gate-Drain Charge			3.5		
T _{d(on)} e	Turn-On Delay Time			11		
T _r e	Rise Time	V_{DD} =30V , V_{GEN} =10V , R_G =6 Ω		7		20
T _{d(off)} e	Turn-Off Delay Time	I _D =1A ,RL=30Ω		28		ns
T _f e	Fall Time			8		
C _{iss} e	Input Capacitance			780		
C _{oss} e	Output Capacitance	V _{DS} =25V , V _{GS} =0V , f=1MHz		45		pF
C _{rss} e	Reverse Transfer Capacitance			30		

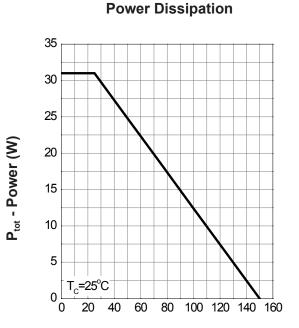
Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V _G =V _D =0V , Force Current			6	Α
V_{SD}^d	Diode Forward Voltage	V_{GS} =0V , I_{S} =1A , T_{J} =25 $^{\circ}$ C			1.2	V
t _{rr}	Reverse Recovery Time	Is=1A,dI/dt=100A/µs		30		nS
Q _{rr}	Reverse Recovery Charge	,		41		nC

Note d : Pulse test ; pulse width $\leq 300 \mu s$, duty cycle $\leq 2\%$.

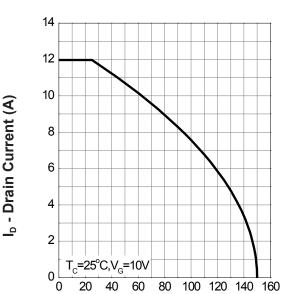
Note \mathbf{e} : Guaranteed by design, not subject to production testing.





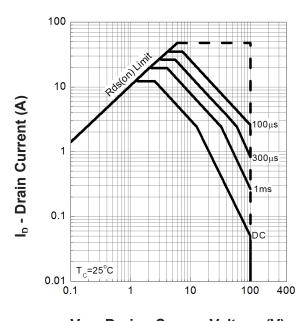
T_i - Junction Temperature (°C)

Drain Current



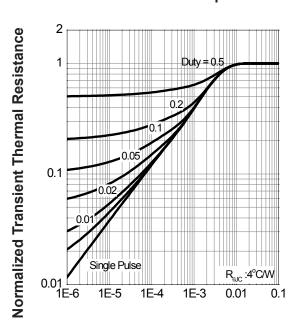
T_i - Junction Temperature (°C)

Safe Operation Area



V_{DS} - Drain - Source Voltage (V)

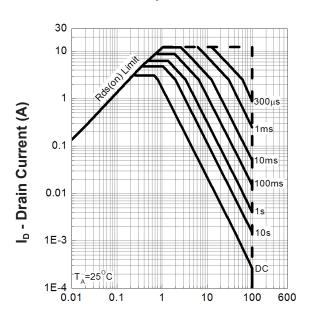
Thermal Transient Impedance



Square Wave Pulse Duration (sec)

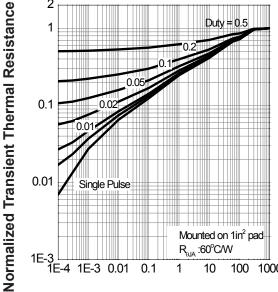


Safe Operation Area



V_{DS} - Drain - Source Voltage (V)

0.01



Single Pulse

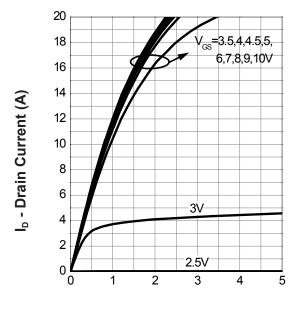
1E-3 L-1 1E-3 0.01

Thermal Transient Impedance

Square Wave Pulse Duration (sec)

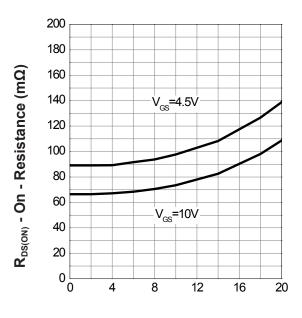
Mounted on 1in² pad

Output Characteristics



V_{DS} - Drain - Source Voltage (V)

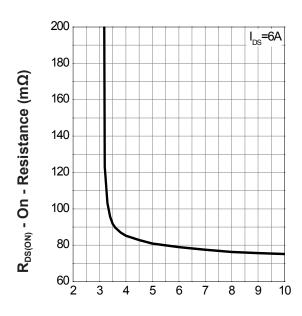
Drain-Source On Resistance



I_D - Drain Current (A)

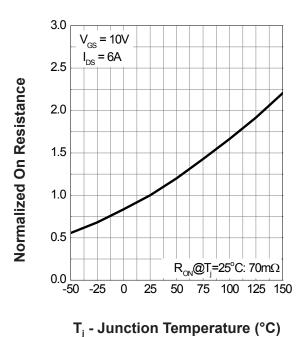


Gate-Source On Resistance

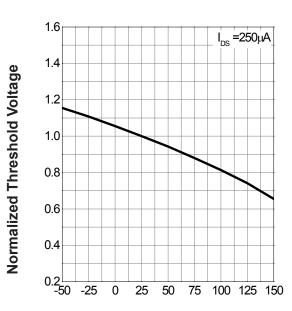


V_{GS} - Gate - Source Voltage (V)

Drain-Source On Resistance

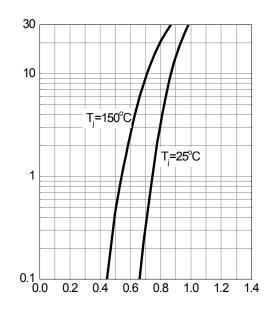


Gate Threshold Voltage



T_i - Junction Temperature (°C)

Source-Drain Diode Forward

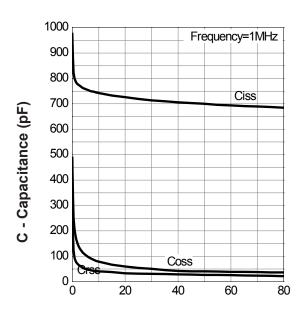


V_{SD} - Source - Drain Voltage (V)

Is - Source Current (A)

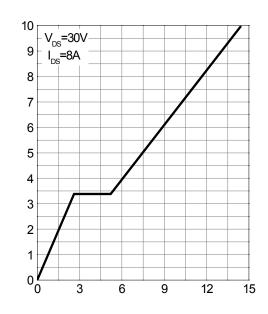


Capacitance



V_{DS} - Drain-Source Voltage (V)

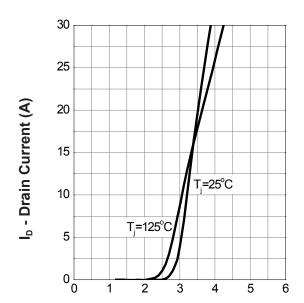
Gate Charge



V_{cs} - Gate-source Voltage (V)

Q_G - Gate Charge (nC)

Transfer Characteristics



V_{GS} - Gate-Source Voltage (V)



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